TOSHIBA DIODE SILICON EPITAXIAL PLANAR TYPE

HN1D01FU

ULTRA HIGH SPEED SWITCHING APPLICATION.

Small Package

Low Forward Voltage : V_{F(3)}=0.92V (Typ.)

• Fast Reverse Recovery Time : $t_{rr} = 1.6ns$ (Typ.)

• Small Total Capacitance : C_T=2.2pF (Typ.)

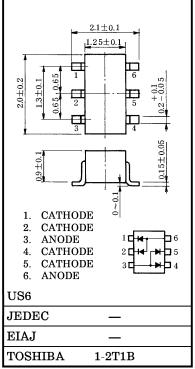
MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	RATING	UNIT	
Maximum (Peak) Reverse Voltage	$v_{ m RM}$	85	5 V	
Reverse Voltage	$V_{ m R}$	80	V	
Maximum (Peak) Forward Current	$I_{ extbf{FM}}$	300*	mA	
Average Forward Current	I_{O}	100*	mA	
Surge Current (10ms)	$I_{ ext{FSM}}$	2*	Α	
Power Dissipation	P	200	mW	
Junction Temperature	T_{j}	125	°C	
Storage Temperature	$T_{ m stg}$	-55~125	$^{\circ}\mathrm{C}$	

* : This is the Maximum Ratings of single diode (Q1 or Q2 or Q3 or Q4).

In the case of using Unit 1 and Unit 2 independently or simultaneously, the Maximum Ratings per diode is 75% of the single diode one.

Unit in mm

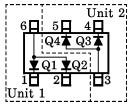


Weight: 6.8mg

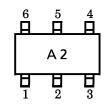
ELECTRICAL CHARACTERISTICS (Q1, Q2, Q3, Q4 COMMON, Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Forward Voltage	$V_{F(1)}$	$I_{\mathbf{F}} = 1 \text{mA}$	_	0.61	_	V
	$V_{F(2)}$	$I_{\mathbf{F}} = 10 \text{mA}$	_	0.74	_	
	$V_{\mathrm{F}(3)}$	$I_{\mathbf{F}} = 100 \text{mA}$	_	0.92	1.20	
Reverse Current	$I_{R(1)}$	$V_R = 30V$	_	_	0.1	μ A
	$I_{R(2)}$	$V_R = 80V$	_	_	0.5	
Total Capacitance	C_{T}	$V_R = 0$, $f = 1MHz$	_	2.2	4.0	pF
Reverse Recovery Time	t_{rr}	$I_{\mathbf{F}} = 10 \text{mA (Fig. 1)}$	_	1.6	4.0	ns

PIN ASSIGNMENT (TOP VIEW)



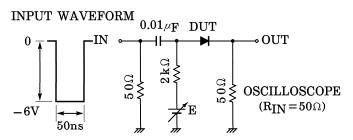
Marking



961001EAA2

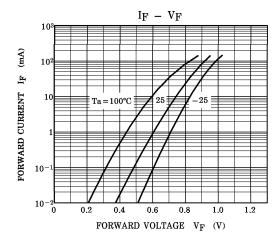
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Fig. 1 REVERSE RECOVERY TIME (t_{rr}) TEST CIRCUIT

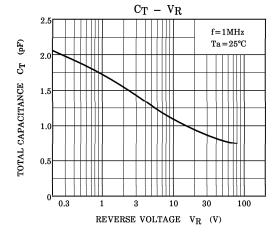


PULSE GENERATOR $(R_{OUT} = 50\Omega)$

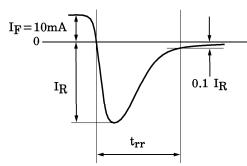
Q1, Q2, Q3, Q4 COMMON



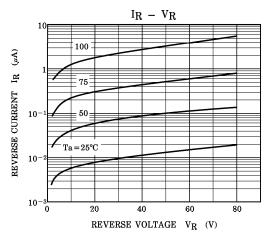
Q1, Q2, Q3, Q4 COMMON



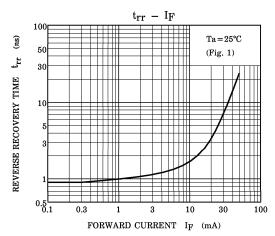
OUTPUT WAVEFORM



Q1, Q2, Q3, Q4 COMMON



Q1, Q2, Q3, Q4 COMMON



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